Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/654,954	CHEN ET AL.
Examiner	Art Unit
Meless N. Zewdu	2617

SEARCHED			
Class	Subclass	Date	Examiner
340	693.3- 693.4	4/3/2007	M.Z.
340	693.1	4/3/2007	M.Z.
340	539.1	4/3/2007	M.Z.
340	539.3	4/3/2007	M.Z.
340	7.32-7.38	4/3/2007	M.Z.
340	10.33	4/3/2007	M.Z.
340	10.34	4/3/2007	M.Z.
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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(INCLUDING SEAR	CH STRATEG	Y)
	DATE	EXMR
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Search Notes (continued)



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10/654,954	CHEN ET AL.
Examiner	Art Unit
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SEARCHED			
Class	Subclass	Date	Examiner
455	343.1- 343.6	4/3/2007	M.Z.
455	127.1	4/3/2007	M.Z.
455	127.5	4/3/2007	M.Z.
455	571-574	4/3/2007	M.Z.
455	91, 13.4	4/3/2007	M.Z.
455	515-517	4/3/2007	M.Z.
455	95, 528	4/3/2007	M.Z.
455	550.1	4/3/2007	M.Z.
455	556.2	4/3/2007	M.Z.
455	560-561	4/3/2007	M.Z.
342	385-386	4/3/2007	M.Z.
713	300, 310	4/3/2007	M.Z.
713	321-324	4/3/2007	M.Z.
713	330, 340	4/3/2007	M.Z.

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Search strategy and techniques  EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT & IBM_TDB)	4/3/2007	M.Z.
Inventor/s search	4/3/2007	M.Z.
Assignee search	4/3/2007	M.Z.
For keywords usage and more, please see the attached search history printout.	4/3/2007	M.Z.
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